
FOREWORD

Special Section on Machine Vision and its Applications

The Eleventh IAPR Conference on Machine Vision Applications, MVA2009, was held in Keio University from May 20 through 22, 2009. Reflecting growing areas of machine vision applications, which include surveillance, measurement, control, interaction, and various object recognition, the conference attracted about 150 submissions from 29 countries in spite of serious recession and swine flu. We selected 39 oral and 83 poster presentations, and the conference was quite active in friendly atmosphere. Encouraged by the great success of the conference, we planned this special section and asked the conference participants and other researchers in this field to submit papers. We received 48 papers, and we have selected 14 papers among them through rigorous review process. We believe that the papers show the high quality of current machine vision research and wide variety of applications. We would like to express our sincere gratitude to all the authors for their valuable contributions and to all the reviewers for their cooperation in completing the reviewing process under a tight schedule.

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Ken-ichi Maeda (*Fellow*) received the B.S. degree in physical electronics, the M.S. degree in electrical engineering, and the Ph.D. degree in information processing from Tokyo Institute of Technology in 1974, 1976, and 2007, respectively. He joined Toshiba Corporation in 1976. He was a visiting scholar at Artificial Intelligence Applications Institute of the University of Edinburgh from 1989 to 1990, Head of Kansai Research Center of Toshiba Corporation from 1999 to 2000, and Senior Fellow at Corporate Research and Development Center, Toshiba Corporation from 2004 to 2009. He is currently Senior Fellow at Toshiba Research Consulting Corporation. His research interests include pattern recognition, computer vision, and computer architecture. Dr. Maeda is Senior Member of IEEE.

